

SAR EVALUATION REPORT

FCC 47 CFR § 2.1093 IEEE Std 1528-2013

For **SMARTPHONE**

FCC ID: BCG-E8441A, BCG-E8442A

Model Name: A3106, A3108

Report Number: 14523773-S1V3 Issue Date: 8/24/2023

Prepared for APPLE INC. 1 APPLE PARK WAY CUPERTINO, CA 95014-2084

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Revision History

Rev.	Date	Revisions	Revised By
V1	8/10/2023	Initial Issue	
V2	8/18/2023	Added iPD test results	Coltyce Sanders
V3	8/24/2023	Section 1 & 7: Updated note	Coltyce Sanders

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1. Attestation of Test Results

Applicant Name	APPLE INC	APPLE INC.						
FCC ID	BCG-E8441	BCG-E8441A, BCG-E8442A						
Model Name	A3106, A310	08						
Applicable Standards		FCC 47 CFR § 2.1093 IEEE Std 1528-2013						
			;	SAR Lim	nits (W/k	(g)		
Exposure Category		Peak spatial-a	· ·		Extremities (hands, wrists, ankles, etc.) (10g of tissue)			
General population / Uncontrolled exposure		1.6					4	
DE Evacoure Conditions		ı	Equipment Clas	s - High	nest Rep	oorted SAR (W/k	(g)	
RF Exposure Conditions	TNE	PCE	CBE	D ⁻	ΓS	NII	DSS	DXX (10g)
Worst Case from BCG-E8440A (A3105)	0.938 0.947 0.949 1.132 1.107 0.917 0.017					0.017		
Variant Models		Worst-Case SAR for Variant Models						
BCG-E8441A (A3106)	0.791	0.797	0.852	0.9	903	0.662	0.927	0.004
BCG-E8442A (A3108)	N/A	0.784	0.775	0.7	778	0.691	0.632	0.006
	Radiofrequency (RF) Radiation Exposure (above 6GHz)							
Exposure Category / Applicable limit	☑ Uncontrolled (mW/cm² over 4 cm²) 30 min average			☐ Occupational/controlled (mW/cm² over 4 cm²) 6 min average				
	1.0				5			
Worst Case from			Highest Reporte	d PD R	esult (m	W/cm² over 4cm	n²)	
BCG-E8440A (A3105)				0.	702			
BCG-E8441A (A3106)	0.569							
BCG-E8442A (A3108)				0.	604			
Date Tested	7/20/2023 to	8/4/2023 and 8	/18/2023					
Test Results	Pass							
	•							

This application for certification is leveraging the data reuse procedure from TCB workshop April 2021; RF Exposure Procedures (Remarks on Test Reductions via Data Referencing for Closely Related Products) based on reference FCC ID: **BCG-E8440A** (UL SAR report# 14523772-S1) and (UL PD report # 14523772-S10) to cover variants FCC ID: **BCG-ECG8441A** and **BCG-ECG8442A**. The major difference between the reference model and the variant models is that support for some LTE/5GNR bands and MSS is disabled via software in the variant models. All other circuitry and features are identical. The data reuse test plan was approved via manufacturer KDB inquiry.

UL Verification Services Inc. tested the above equipment in accordance with the requirements set forth in the above standards. The test results show that the equipment tested can demonstrate compliance with the requirements as documented in this report.

This report contains data provided by the customer which can impact the validity of results. UL Verification Services Inc. is only responsible for the validity of results after the integration of the data provided by the customer.

The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. It is the manufacturer's responsibility to assure that additional production units of this model are manufactured with identical electrical and mechanical components. All samples tested were in good operating condition throughout the entire test program. Measurement Uncertainties are published for informational purposes only and were not considered unless noted otherwise.

This document may not be altered or revised in any way unless done so by UL Verification Services Inc. and all revisions are noted in the revisions section. Any alteration of this document not carried out by UL Verification Services Inc. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by A2LA, NIST, any agency of the Federal Government, or any agency of the U.S. government.

Approved & Released By:	Prepared By:
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UL Verification Services Inc.	UL Verification Services Inc.

2. Test Specification, Methods and Procedures

The tests documented in this report were performed in accordance with FCC 47 CFR § 2.1093, IEEE Std 1528-2013, the following FCC Published RF exposure KDB procedures:

- o 248227 D01 802.11 Wi-Fi SAR v02r02
- o 447498 D01 General RF Exposure Guidance v06
- o 447498 D03 Supplement C Cross-Reference v01
- 648474 D04 Handset SAR v01r03
- 865664 D01 SAR measurement 100 MHz to 6 GHz v01r04
- 865664 D02 RF Exposure Reporting v01r02
- 941225 D01 3G SAR Procedures v03r01
- o 941225 D05 SAR for LTE Devices v02r05
- o 941225 D05A LTE Rel.10 KDB Inquiry Sheet v01r02
- 941225 D06 Hotspot Mode v02r01

In addition to the above, the following information was used:

- o TCB workshop October 2014; RF Exposure Procedures (Other LTE Considerations)
- TCB workshop April 2015; RF Exposure Procedures (Overlapping LTE Bands)
- o TCB workshop October 2015; RF Exposure Procedures (KDB 941225 D05A)
- TCB workshop April 2016; RF Exposure Procedures (LTE Carrier Aggregation for DL)
- o TCB workshop October 2016; RF Exposure Procedures (LTE Carrier Aggregation for UL)
- TCB workshop October 2016; RF Exposure Procedures (Bluetooth Duty Factor)
- TCB workshop October 2016; RF Exposure Procedures (DUT Holder Perturbations)
- TCB workshop May 2017; RF Exposure Procedures (Broadband Liquid Above 3 GHz)
- TCB workshop May 2017; RF Exposure Procedures (LTE Band 41 Power Class 2)
- TCB workshop November 2017; RF Exposure Procedures (LTE UL/DL Carrier Aggregation SAR)
- TCB workshop April 2018; RF Exposure Procedures (LTE DL CA SAR Test Exclusion)
- TCB workshop October 2018; RF Exposure Procedures (LTE Inter-Band Uplink Carrier Aggregation Interim Procedures)
- TCB workshop April 2019; RF Exposure Procedures (802.11ax SAR Testing)
- TCB workshop November 2019; RF Exposure Policy Updates (5G NR FR1 NSA EN-DCUE SAR Evaluations)
- o TCB workshop October 2020; 5G and RF Exposure Procedures (U-NII 6-7 GHz SAR Testing)
- TCB workshop April 2021; RF Exposure Procedures (Remarks on Test Reductions via Data Referencing for Closely Related Products)

3. Facilities and Accreditation

The test sites and measurement facilities used to collect data are located at

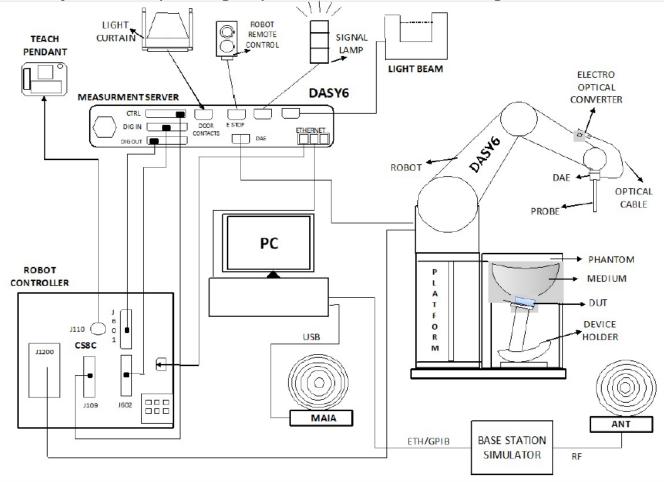
47173 Benicia Street	47266 Benicia Street
SAR Labs A to I	SAR Labs 1 to 19

UL Verification Services Inc. is accredited by A2LA, Certificate Number 0751.05

4. SAR Measurement System & Test Equipment

4.1. SAR Measurement System

The DASY system used for performing compliance tests consists of the following items:



- A standard high precision 6-axis robot with controller, teach pendant and software. An arm extension for accommodating the data acquisition electronics (DAE).
- An isotropic Field probe optimized and calibrated for the targeted measurement.
- A data acquisition electronics (DAE) which performs the signal amplification, signal multiplexing, ADconversion, offset measurements, mechanical surface detection, collision detection, etc. The unit is battery powered with standard or rechargeable batteries. The signal is optically transmitted to the EOC.
- The Electro-optical converter (EOC) performs the conversion from optical to electrical signals for the digital communication to the DAE. To use optical surface detection, a special version of the EOC is required. The EOC signal is transmitted to the measurement server.
- The function of the measurement server is to perform the time critical tasks such as signal filtering, control of the robot operation and fast movement interrupts.
- The Light Beam used is for probe alignment. This improves the (absolute) accuracy of the probe positioning.
- A computer running Win10 and the DASY6/8¹ software.
- Remote control and teach pendant as well as additional circuitry for robot safety such as warning lamps, etc.
- The phantom, the device holder, and other accessories according to the targeted measurement.

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¹ DASY6/8 software used: DASY6.16.2 or DASY8.16.2 and older generations.

4.2. SAR Scan Procedures

Step 1: Power Reference Measurement

The Power Reference Measurement and Power Drift Measurements are for monitoring the power drift of the device under test in the batch process. The minimum distance of probe sensors to surface determines the closest measurement point to phantom surface. The minimum distance of probe sensors to surface is 2.1 mm. This distance cannot be smaller than the distance of sensor calibration points to probe tip as defined in the probe properties.

Step 2: Area Scan

The Area Scan is used as a fast scan in two dimensions to find the area of high field values, before doing a fine measurement around the hot spot. The sophisticated interpolation routines implemented in DASY software can find the maximum locations even in relatively coarse grids. When an Area Scan has measured all reachable points, it computes the field maximal found in the scanned area, within a range of the global maximum. The range (in dB) is specified in the standards for compliance testing. For example, a 2 dB range is required in IEC/IEEE 62209-1528, whereby 3 dB is a requirement when compliance is assessed in accordance with the ARIB standard (Japan). If only one Zoom Scan follows the Area Scan, then only the absolute maximum will be taken as reference. For cases where multiple maximums are detected, the number of Zoom Scans has to be increased accordingly.

Area Scan Parameters extracted from KDB 865664 D01 SAR Measurement 100 MHz to 6 GHz

	≤ 3 GHz	> 3 GHz
Maximum distance from closest measurement point (geometric center of probe sensors) to phantom surface	5 ± 1 mm	$\frac{1}{2} \cdot \delta \cdot \ln(2) \pm 0.5 \text{ mm}$
Maximum probe angle from probe axis to phantom surface normal at the measurement location	30° ± 1°	20° ± 1°
	≤ 2 GHz: ≤ 15 mm 2 – 3 GHz: ≤ 12 mm	$3 - 4 \text{ GHz:} \le 12 \text{ mm}$ $4 - 6 \text{ GHz:} \le 10 \text{ mm}$
Maximum area scan spatial resolution: Δx_{Area} , Δy_{Area}	When the x or y dimension of measurement plane orientation the measurement resolution of x or y dimension of the test of measurement point on the test	on, is smaller than the above, must be \leq the corresponding levice with at least one

Step 3: Zoom Scan

Zoom Scans are used to assess the peak spatial SAR values within a cubic averaging volume containing 1 g and 10 g of simulated tissue. The Zoom Scan measures points (refer to table below) within a cube whose base faces are centered on the maxima found in a preceding area scan job within the same procedure. When the measurement is done, the Zoom Scan evaluates the averaged SAR for 1 g and 10 g and displays these values next to the job's label.

Zoom Scan Parameters extracted from KDB 865664 D01 SAR Measurement 100 MHz to 6 GHz

			≤ 3 GHz > 3 GHz	
Maximum zoom scan spatial resolution: Δx_{Zoom} , Δy_{Zoom}			\leq 2 GHz: \leq 8 mm 2 – 3 GHz: \leq 5 mm	$3 - 4 \text{ GHz: } \le 5 \text{ mm}^*$ $4 - 6 \text{ GHz: } \le 4 \text{ mm}^*$
	uniform grid: $\Delta z_{Zoom}(n)$		≤ 5 mm	3 – 4 GHz: ≤ 4 mm 4 – 5 GHz: ≤ 3 mm 5 – 6 GHz: ≤ 2 mm
Maximum zoom scan spatial resolution, normal to phantom surface	n,	Δz _{Zoom} (1): between 1 st two points closest to phantom surface	≤ 4 mm	$3 - 4 \text{ GHz: } \le 3 \text{ mm}$ $4 - 5 \text{ GHz: } \le 2.5 \text{ mm}$ $5 - 6 \text{ GHz: } \le 2 \text{ mm}$
	grid $\Delta z_{Zoom}(n>1)$: between subsequent points		$\leq 1.5 \cdot \Delta z_{Zoom}(n-1)$	
Minimum zoom scan volume	X. V. 7		≥ 30 mm	$3 - 4 \text{ GHz:} \ge 28 \text{ mm}$ $4 - 5 \text{ GHz:} \ge 25 \text{ mm}$ $5 - 6 \text{ GHz:} \ge 22 \text{ mm}$

Note: δ is the penetration depth of a plane-wave at normal incidence to the tissue medium; see draft standard IEEE P1528-2011 for details.

Step 4: Power drift measurement

The Power Drift Measurement measures the field at the same location as the most recent power reference measurement within the same procedure, and with the same settings. The Power Drift Measurement gives the field difference in dB from the reading conducted within the last Power Reference Measurement. This allows a user to monitor the power drift of the device under test within a batch process. The measurement procedure is the same as Step 1.

When zoom scan is required and the <u>reported</u> SAR from the <u>area scan based 1-g SAR estimation</u> procedures of KDB 447498 is ≤ 1.4 W/kg, ≤ 8 mm, ≤ 7 mm and ≤ 5 mm zoom scan resolution may be applied, respectively, for 2 GHz to 3 GHz, 3 GHz to 4 GHz and 4 GHz to 6 GHz.

4.3. Power Density Measurement System

4.3.1. EUmmWVx / E-Field 5G Probe

E-Field mm-Wave Probe for General Near-Field Measurements

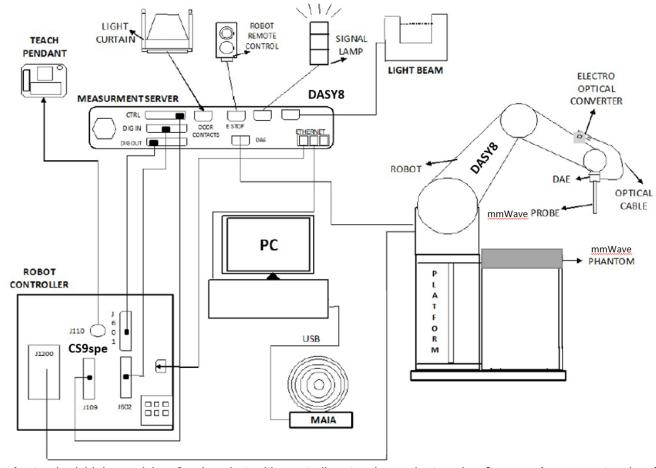
•	Two dipoles optimally arranged to obtain pseudo-vector information Minimum 3 measurements/point, 120° rotated around probe axis Sensors (0.8mm length) printed on glass substrate protected by high density foam Low perturbation of the measured field Requires positioner which can do accurate probe rotation
Frequency Range	750 MHz – 110 GHz (EUmmWV4)
Dynamic Range	< 20 V/m - 10'000 V/m with PRE-10 (min < 50 V/m - 3000 V/m)
Position Precision	< 0.2 mm (DASY8)
Dimensions	Overall length: 337 mm (tip: 20 mm) Tip diameter: encapsulation 8 mm (internal sensor < 1mm) Distance from probe tip to dipole centers: < 2 mm Sensor displacement to probe's calibration point: < 0.3 mm
Applications	E-field measurements of 5G devices and other mm-wave transmitters operating above 6GHz in < 2 mm distance from device (free-space) Power density, H-field and far-field analysis using total field reconstruction (DASY8 Module mmWave)
Compatibility	cDASY6/8 Module mmWave V3.2.2.2358

4.3.2. Data Acquisition Electronics(DAE)

	Serial optical link for communication with DASY embedded system (fully remote controlled) Two-step probe touch detector for mechanical surface detection and emergency robsot stop
Measurement Range	-100 - +300 mV (16 bit resolution and two range settings: 4 mV, 400 mV)
Input Offset Voltage	<5 μV (with auto zero)
Input Resistance	200 Mohm
Input Bias Current	<50 fA
Battery Power	>10 hours of operation (with two 9.6 V NiMH batteries)
Dimensions (L × W × H)	60 × 60 × 68 mm

4.3.3. Measurement System

The DASY6/8 system used for performing compliance tests consists of the following items:



- A standard high precision 6-axis robot with controller, teach pendant and software. An arm extension for accommodating the data acquisition electronics (DAE).
- The EUmmWVx probe is based on the pseudo-vector probe design, which not only measures the field magnitude but also derives its polarization ellipse.
- A data acquisition electronics (DAE) which performs the signal amplification, signal multiplexing, ADconversion, offset measurements, mechanical surface detection, collision detection, etc. The unit is battery powered with standard or rechargeable batteries. The signal is optically transmitted to the EOC.
- The Electro-optical converter (EOC) performs the conversion from optical to electrical signals for the digital communication to the DAE. To use optical surface detection, a special version of the EOC is required. The EOC signal is transmitted to the measurement server.
- The function of the measurement server is to perform the time critical tasks such as signal filtering, control of the robot operation and fast movement interrupts.
- The Light Beam used is for probe alignment. This improves the (absolute) accuracy of the probe positioning.
- A computer running Win10 and the DASY6/8² software.
- Remote control and teach pendant as well as additional circuitry for robot safety such as warning lamps, etc.
- The phantom which is specialized for 5G other accessories according to the targeted measurement.

² DASY8 software used: DASY6/8 mmWave V3.2.2.2358 and older generations.

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4.4. Power Density Measurement Procedures

4.4.1. System Verification Scan Procedures

cDASY6/8 Module mmWave supports "5G Scan", a fine resolution scan performed on two different planes which is used to reconstruct the E- and H-fields as well as the power density; the average power density is derived from this measurement.

Step 1: Power Reference Measurement

The Power Reference Measurement and Power Drift Measurements are for monitoring the power drift of the device under test in the batch process. The minimum distance of probe sensors to surface determines the closest measurement point to devise under test.

Step 2: 5G Scan

The steps in the X, Y, and Z directions are specified in terms of fractions of the signal wavelength, lambda. Area Scan Parameters extracted from SPEAG cDASY6 System Handbook; part 4 cDASY6/8 Module mmWave.

Recommended settings for measurement of verification sources

Frequency	Grid		Grid extent X/Y	Measurement	
[GHz]	step		[mm]	points	
10	0.125 $\left(\frac{\lambda}{8}\right)$		60/60	18×18	
30	0.25	$\left(\frac{\lambda}{4}\right)$	60/60	26×26	
45	0.25	$\left(\frac{\lambda}{4}\right)$	42/42	28×28	
60	0.25	$\left(\frac{\lambda}{4}\right)$	32.5/32.5	28×28	
90	0.25	$\left(\frac{\lambda}{4}\right)$	30/30	38×38	

The minimum distance of probe sensors to the verification source surface, horn antenna, is 10 mm for 10 GHz and 5.55mm for 30 GHz and above.

Step 3: Power drift measurement

The Power Drift Measurement measures the field at the same location as the most recent power reference measurement within the same procedure, and with the same settings. The Power Drift Measurement gives the field difference in dB from the reading conducted within the last Power Reference Measurement. This allows a user to monitor the power drift of the device under test within a batch process. The measurement procedure is the same as Step 1.

When the drift is larger than ± 5 %, the test is repeated from step1.

4.4.2. Scan Procedures

Step 1: Power Reference Measurement

Same as System Verification Scan Procedures step 1.

Step 2: 5G Scan

Same as System Verification Scan Procedures step 2. But measurement area is defined based on TCB workshop April 2019, "A sufficiently large measurement region and proper measurement spatial resolution are required to maintain field reconstruction accuracy".

-Fields at the measurement region boundary should be ~20-30 dB below the peaks

Step 3: Power drift measurement

Same as System Verification Scan Procedures step 3.

When the drift is smaller than ± 5 %, it is considered in the uncertainty budget if drifts larger than 5%, uncertainty is re-calculated.

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4.5. Test Equipment

The measuring equipment used to perform the tests documented in this report has been calibrated in accordance with the manufacturers' recommendations and is traceable to recognized national standards.

Dielectric Property Measurements

Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
Vector Network Analyzer	ROHDE & SCHWARZ	ZNLE6	101274-mn	2/19/2024
Dielectric Probe kit	SPEAG	DAK-3.5	1103	2/28/2024
Shorting Block	SPEAG	DAK-1.2/3.5 Short	SM DAK 200 BA	2/28/2024
Thermometer	Fisher Scientific	Traceable	122529162	8/9/2023
Vector Network Analyzer	ROHDE & SCHWARZ	ZNLE6	101273-VA	2/19/2024
Dielectric Probe kit	SPEAG	DAK-3.5	1082	9/19/2023
Dielectric Probe kit	SPEAG	DAK-12	1128	1/16/2024
Shorting Block	SPEAG	DAK-1.2/3.5 Short	SM DAK 200 BA	9/19/2023
Shorting Block	SPEAG	DAK-12 Short	SM DAK 220 AC	1/16/2024
Thermometer	Fisher Scientific	Traceable	140493798	4/30/2024
Vector Network Analyzer	Copper Mountain Tech	R140N	21130078	4/30/2024
Dielectric Probe kit	SPEAG	DAK-3.5	1087	11/17/2023
Shorting Block	SPEAG	DAK-1.2/3.5 Short	SM DAK 200 BA	11/17/2023
Thermometer	Fisher Scientific	Traceable	170064398	4/10/2024

System Check

Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
MXG Analog Signal Generator	Agilent	N5181A	MY50140610	1/31/2024
Pow er Meter	HP	437B	3125U11364	1/31/2024
Pow er Meter	HP	437B	3125U11347	1/31/2024
Pow er Sensor	HP	8481A	3318A92374	1/31/2024
Pow er Sensor	HP	8481A	1926A27049	1/31/2024
Amplifier	Miteq	AMF-4D-00400600-50-30P	1795093	N/A
Bi-directional coupler	Werlatone	C8060-102	2711	N/A
DC Pow er Supply	Sorensen	XT 15-4	1802A01877	N/A
MXG Analog Signal Generator	Agilent	N5181A	MY50140630	1/31/2024
Pow er Meter	Keysight	N1912A	MY55196004	1/31/2024
Pow er Sensor	Agilent	N1921A	MY53260010	1/31/2024
Pow er Sensor	Agilent	N1921A	MY52260009	1/31/2024
Amplifier	Miteq	AMF-4D-00400600-50-30P	1795092	N/A
Bi-directional coupler	Werlatone	C8060-102	2149	N/A
DC Pow er Supply	Sorensen	XT 15-4	PRE0178948	N/A
Signal Genarator	R&S	SMB 100A	171706	2/29/2024
Pow er Meter	Keysight	N1912A	MY55196007	1/31/2024
Pow er Sensor	Agilent	N1921A	MY53020038	1/31/2024
Pow er Sensor	R&S	NRP18A	171503	2/29/2024
Bi-directional coupler	Werlatone	C8060-102	4054	N/A

Lab Equipment

Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
E-Field Probe (SAR Lab D)	SPEAG	EX3DV4	7587	4/18/2024
E-Field Probe (SAR Lab 2)	SPEAG	EX3DV4	3989	1/26/2024
E-Field Probe (SAR Lab 3)	SPEAG	EUmmWV4	9589	9/20/2024
E-Field Probe (SAR Lab 8)	SPEAG	EX3DV4	7807	4/11/2024
E-Field Probe (SAR Lab 13)	SPEAG	EX3DV4	3990	2/17/2024
Data Acquisition Electronics (SAR Lab D)	SPEAG	DAE4	1239	3/16/2024
Data Acquisition Electronics (SAR Lab 2)	SPEAG	DAE4	1257	9/20/2023
Data Acquisition Electronics (SAR Lab 3)	SPEAG	DAE4	1377	9/15/2023
Data Acquisition Electronics (SAR Lab 8)	SPEAG	DAE4	1799	4/4/2024
Data Acquisition Electronics (SAR Lab 13)	SPEAG	DAE4	1545	2/14/2024
Thermometer	TRACEABLE	6530CC	170361	2/29/2024
Thermometer	TRACEABLE	6530CC	155512	2/29/2024
Thermometer	TRACEABLE	6530CC	174046	2/29/2024
System Validation Dipole	SPEAG	CLA13	1008	1/12/2024
System Validation Dipole	SPEAG	D1900V2	5d163	10/28/2023
System Validation Dipole	SPEAG	D2450V2	706	1/20/2024
System Validation Dipole	SPEAG	D2450V2	899	4/18/2024
System Validation Dipole	SPEAG	D2600V2	1036	4/11/2024
System Validation Dipole	SPEAG	D3700V2	1110	11/20/2023
5G Verification Source	SPEAG	5G Verification Source 10GHz	1015	9/13/2023

Other

Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
Pow er Meter	Keysight	N1911A	MY55196015	1/31/2024
Pow er Sensor	Agilent	N1921A	MY52270022	1/31/2024
Wideband Radio Communication Tester	R&S	CMW500	80580	2/29/2024
Wideband Radio Communication Tester	R&S	CMW500	85780	2/29/2024
Wideband Radio Communication Tester	R&S	CMW500	208643	2/29/2024
Wideband Radio Communication Tester	R&S	CMW500	208049	2/29/2024
Wideband Radio Communication Tester	R&S	CMW500	81849	2/29/2024
Wideband Radio Communication Tester	R&S	CMW500	85781	2/29/2024

5. Measurement Uncertainty

SAR

Per KDB 865664 D01 SAR Measurement 100 MHz to 6 GHz, when the highest measured 1-g SAR within a frequency band is < 1.5 W/kg and the measured 10-g SAR within a frequency band is < 3.75 W/kg. The expanded SAR measurement uncertainty must be \leq 30%, for a confidence interval of k = 2. If these conditions are met, extensive SAR measurement uncertainty analysis described in IEEE Std 1528-2013 is not required in SAR reports submitted for equipment approval.

Therefore, the measurement uncertainty is not required.

Power Density

Error Description	Power D	<u>ensity</u>						
Uncertainty terms dependent on the measurement system		а	b	С	-	е		g
CAL Calibration Repeatability 0.49 Normal 1 1 0.49 ∞ COR Probe correction 0 Rectangular 1.732 1 0.00 ∞ FRS Frequency response (BW □ GHz) 0.20 Rectangular 1.732 1 0.12 ∞ SCC Sensor cross coupling 0 Rectangular 1.732 1 0.00 ∞ ISO Isotropy 0.50 Rectangular 1.732 1 0.29 ∞ LIN Linearity 0.20 Rectangular 1.732 1 0.00 ∞ PSC Probe scattering 0 Rectangular 1.732 1 0.00 ∞ PPC Probe positioning oset 0.30 Rectangular 1.732 1 0.00 ∞ SMO Sensor mechanical oset 0 Rectangular 1.732 1 0.00 ∞ PSR Probe positioning repeatability 0.04 Rectangular 1.732 1 </td <td></td> <td>Error Description</td> <td>_</td> <td></td> <td>Div.</td> <td>ci</td> <td></td> <td>vi</td>		Error Description	_		Div.	ci		vi
COR Probe correction 0 Rectangular 1.732 1 0.00 ∞ FRS Frequency response (BW □1 GHz) 0.20 Rectangular 1.732 1 0.12 ∞ SCC Sensor cross coupling 0 Rectangular 1.732 1 0.29 ∞ LIN Linearity 0.20 Rectangular 1.732 1 0.29 ∞ LIN Linearity 0.20 Rectangular 1.732 1 0.12 ∞ PSC Probe scattering 0 Rectangular 1.732 1 0.12 ∞ PPO Probe positioning oset 0.30 Rectangular 1.732 1 0.00 ∞ SMO Sensor mechanical oset 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ FLD Field impedance dependance 0 Rectangular 1.732 1 <td>Uncertain</td> <td>ty terms dependent on the measuremen</td> <td>nt system</td> <td></td> <td></td> <td></td> <td></td> <td></td>	Uncertain	ty terms dependent on the measuremen	nt system					
FRS Frequency response (BW □1 GHz) 0.20 Rectangular 1.732 1 0.12 ∞ SCC Sensor cross coupling 0 Rectangular 1.732 1 0.00 ∞ LIN Linearity 0.50 Rectangular 1.732 1 0.29 ∞ PSC Probe scattering 0 Rectangular 1.732 1 0.12 ∞ PPO Probe positioning or set 0.30 Rectangular 1.732 1 0.17 ∞ PPR Probe positioning repeatability 0.04 Rectangular 1.732 1 0.02 ∞ SMO Sensor mechanical or Set 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ FLD Field impedance dependance 0 Rectangular 1.732 1 0.00 ∞ APD Amplitude and phase drift 0 Rectangular	CAL	Calibration Repeatability	0.49	Normal	1	1	0.49	∞
SCC Sensor cross coupling 0 Rectangular 1.732 1 0.00 ∞ ISO Isotropy 0.50 Rectangular 1.732 1 0.29 ∞ LIN Linearity 0.20 Rectangular 1.732 1 0.12 ∞ PSC Probe scattering 0 Rectangular 1.732 1 0.00 ∞ PSC Probe positioning o'set 0.30 Rectangular 1.732 1 0.17 ∞ PPR Probe positioning repeatability 0.04 Rectangular 1.732 1 0.00 ∞ PSR Probe positioning repeatability 0.04 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ PSR Probe coupling with DUT 0 Rectangular 1.732 1 0.00 ∞ PSR Probe coupling with DUT 0 Rectangular 1.732 1 0.00 ∞ PSR Probe coupling with DUT 0 Rectangular 1.732 1 0.00 ∞ PSR Probe coupling with DUT 0 Rectangular 1.732 1	COR	Probe correction	0	Rectangular	1.732	1	0.00	∞
ISO Isotropy 0.50 Rectangular 1.732 1 0.29 ∞	FRS	Frequency response (BW 🗆1 GHz)	0.20	Rectangular	1.732	1	0.12	∞
LIN Linearity	SCC	Sensor cross coupling	-	Rectangular	1.732	1	0.00	∞
PSC Probe scattering 0 Rectangular 1.732 1 0.00 ∞ PPO Probe positioning oiset 0.30 Rectangular 1.732 1 0.17 ∞ PPR Probe positioning repeatability 0.04 Rectangular 1.732 1 0.02 ∞ SMO Sensor mechanical oiset 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ FLD Field impedance dependance 0 Rectangular 1.732 1 0.00 ∞ APD Amplitude and phase drift 0 Rectangular 1.732 1 0.00 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ SMP Sampling 0 Rectangular		Isotropy	0.50	Rectangular		1	0.29	∞
PPO Probe positioning oiset 0.30 Rectangular 1.732 1 0.17 ∞ PPR Probe positioning repeatability 0.04 Rectangular 1.732 1 0.02 ∞ SMO Sensor mechanical oiset 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ FLD Field impedance dependance 0 Rectangular 1.732 1 0.00 ∞ APD Amplitude and phase drift 0 Rectangular 1.732 1 0.00 ∞ APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.00 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ TR Measurement area truncation 0 <td< td=""><td>LIN</td><td><u> </u></td><td>0.20</td><td>Rectangular</td><td></td><td>1</td><td>0.12</td><td>∞</td></td<>	LIN	<u> </u>	0.20	Rectangular		1	0.12	∞
PPR Probe positioning repeatability 0.04 Rectangular 1.732 1 0.02 ∞ SMO Sensor mechanical orset 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ FLD Filed impedance dependance 0 Rectangular 1.732 1 0.00 ∞ APD Amplitude and phase drift 0 Rectangular 1.732 1 0.00 ∞ APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.00 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ DAQ Data acquisition 0.03 Normal 1 1 0.00 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 </td <td>PSC</td> <td>Probe scattering</td> <td>0</td> <td>Rectangular</td> <td>1.732</td> <td>1</td> <td>0.00</td> <td>∞</td>	PSC	Probe scattering	0	Rectangular	1.732	1	0.00	∞
SMO Sensor mechanical o set 0 Rectangular 1.732 1 0.00 ∞ PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ FLD Field impedance dependance 0 Rectangular 1.732 1 0.00 ∞ APD Amplitude and phase noise 0.04 Rectangular 1.732 1 0.00 ∞ APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.00 ∞ APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.02 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ DAQ Data acquisition 0.03 Normal 1 1 0.00 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732	PPO	·	0.30	Rectangular	1.732	1	0.17	∞
PSR Probe spatial resolution 0 Rectangular 1.732 1 0.00 ∞ FLD Field impedance dependance 0 Rectangular 1.732 1 0.00 ∞ APD Amplitude and phase drift 0 Rectangular 1.732 1 0.00 ∞ APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.02 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ DAQ Data acquisition 0.03 Normal 1 1 0.03 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.00 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 <t< td=""><td>PPR</td><td>Probe positioning repeatability</td><td>0.04</td><td>Rectangular</td><td>1.732</td><td>1</td><td>0.02</td><td>∞</td></t<>	PPR	Probe positioning repeatability	0.04	Rectangular	1.732	1	0.02	∞
FLD Field impedance dependance 0 Rectangular 1.732 1 0.00 ∞ APD Amplitude and phase drift 0 Rectangular 1.732 1 0.00 ∞ APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.02 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ DAQ Data acquisition 0.03 Normal 1 1 0.03 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.00 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1	SMO	Sensor mechanical oset	0	Rectangular	1.732	1	0.00	∞
APD Amplitude and phase drift 0 Rectangular 1.732 1 0.00 ∞ APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.02 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ DAQ Data acquisition 0.03 Normal 1 1 0.03 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.05 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 0.00 ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1 <td>PSR</td> <td>Probe spatial resolution</td> <td>0</td> <td>Rectangular</td> <td></td> <td>1</td> <td>0.00</td> <td>∞</td>	PSR	Probe spatial resolution	0	Rectangular		1	0.00	∞
APN Amplitude and phase noise 0.04 Rectangular 1.732 1 0.02 ∞ TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ DAQ Data acquisition 0.03 Normal 1 1 0.03 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.00 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 0.00 ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1	FLD		0	Rectangular	1.732	1	0.00	∞
TR Measurement area truncation 0 Rectangular 1.732 1 0.00 ∞ DAQ Data acquisition 0.03 Normal 1 1 0.03 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.00 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 0.00 ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.06 ∞ BC Probe coupling with DUT 0 Rectangular 1.732 1 0.02 ∞ MOD Modulation response 0.40 Rectangular 1.732 1	APD	Amplitude and phase drift	0	Rectangular	1.732	1	0.00	∞
DAQ Data acquisition 0.03 Normal 1 1 0.03 ∞ SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.35 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 - ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0.02 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time </td <td>APN</td> <td>Amplitude and phase noise</td> <td>0.04</td> <td>Rectangular</td> <td>1.732</td> <td>1</td> <td>0.02</td> <td>∞</td>	APN	Amplitude and phase noise	0.04	Rectangular	1.732	1	0.02	∞
SMP Sampling 0 Rectangular 1.732 1 0.00 ∞ REC Field reconstruction 0.60 Rectangular 1.732 1 0.35 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 - ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0.02 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time <td>TR</td> <td>Measurement area truncation</td> <td>0</td> <td>Rectangular</td> <td>1.732</td> <td>1</td> <td>0.00</td> <td>∞</td>	TR	Measurement area truncation	0	Rectangular	1.732	1	0.00	∞
REC Field reconstruction 0.60 Rectangular 1.732 1 0.35 ∞ TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 - ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DAQ DUT alignment <td>DAQ</td> <td>Data acquisition</td> <td>0.03</td> <td>Normal</td> <td>1</td> <td>1</td> <td>0.03</td> <td>∞</td>	DAQ	Data acquisition	0.03	Normal	1	1	0.03	∞
TRA Forward transformation 0 Rectangular 1.732 1 0.00 ∞ SCA Power density scaling - Rectangular 1.732 1 - ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions	SMP	Sampling	0	Rectangular	1.732	1	0.00	∞
SCA Power density scaling - Rectangular 1.732 1 - ∞ SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0.02 ∞ AC RF ambient conditions <td>REC</td> <td>Field reconstruction</td> <td>0.60</td> <td>Rectangular</td> <td>1.732</td> <td>1</td> <td>0.35</td> <td>8</td>	REC	Field reconstruction	0.60	Rectangular	1.732	1	0.35	8
SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0.06 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections<	TRA	Forward transformation	0	Rectangular	1.732	1	0.00	∞
SAV Spatial averaging 0.10 Rectangular 1.732 1 0.06 ∞ SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0.06 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections<	SCA	Power density scaling	-	Rectangular	1.732	1	-	∞
SDL System detection limit 0.04 Rectangular 1.732 1 0.02 ∞ Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 <td>SAV</td> <td></td> <td>0.10</td> <td></td> <td>1.732</td> <td>1</td> <td>0.06</td> <td>∞</td>	SAV		0.10		1.732	1	0.06	∞
Uncertainty terms dependent on the DUT and environmental factors PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 Rectangular 1.732 1 0.12 ∞ DRI Drift of the DUT	SDL	System detection limit	0.04		1.732	1	0.02	∞
PC Probe coupling with DUT 0 Rectangular 1.732 1 0 ∞ MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 Rectangular 1.732 1 0.12 ∞ DRI Drift of the DUT 0.21 Rectangular 1.732 1 0.	Uncertain	ty terms dependent on the DUT and env	rironmental f				1	
MOD Modulation response 0.40 Rectangular 1.732 1 0.23 ∞ IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 Rectangular 1.732 1 0 ∞ DRI Drift of the DUT 0.21 Rectangular 1.732 1 0.12 ∞ Combined Standard Uncertainty Uc(f) = RSS 0.76 ∞		· ·			1.732	1	0	∞
IT Integration time 0 Rectangular 1.732 1 0 ∞ RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 Rectangular 1.732 1 0 ∞ DRI Drift of the DUT 0.21 Rectangular 1.732 1 0.12 ∞ Combined Standard Uncertainty Uc(f) = RSS 0.76 ∞	MOD		0.40		1.732	1	0.23	∞
RT Response time 0 Rectangular 1.732 1 0 ∞ DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 Rectangular 1.732 1 0 ∞ DRI Drift of the DUT 0.21 Rectangular 1.732 1 0.12 ∞ Combined Standard Uncertainty Uc(f) = RSS 0.76 ∞	IT	·	0		1.732	1	0	∞
DH Device holder influence 0.10 Rectangular 1.732 1 0.06 ∞ DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 Rectangular 1.732 1 0 ∞ DRI Drift of the DUT 0.21 Rectangular 1.732 1 0.12 ∞ Combined Standard Uncertainty Uc(f) = RSS 0.76 ∞	RT	Response time	0	_	1.732	1	0	∞
DAQ DUT alignment 0 Rectangular 1.732 1 0 ∞ AC RF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ AR Ambient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSI Immunity / secondary reception 0 Rectangular 1.732 1 0 ∞ DRI Drift of the DUT 0.21 Rectangular 1.732 1 0.12 ∞ Combined Standard Uncertainty Uc(f) = RSS 0.76 ∞		Device holder influence	0.10		1.732	1	0.06	∞
ACRF ambient conditions 0.04 Rectangular 1.732 1 0.02 ∞ ARAmbient reflections 0.04 Rectangular 1.732 1 0.02 ∞ MSIImmunity / secondary reception 0 Rectangular 1.732 1 0 ∞ DRIDrift of the DUT 0.21 Rectangular 1.732 1 0.12 ∞ Combined Standard Uncertainty Uc(f) =RSS 0.76 ∞	DAQ	DUT alignment	0		1.732	1	0	∞
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$			0.04			1	0.02	∞
MSIImmunity / secondary reception0Rectangular1.73210 ∞ DRIDrift of the DUT0.21Rectangular1.73210.12 ∞ Combined Standard Uncertainty Uc(f) =RSS0.76 ∞	-						t	
DRI Drift of the DUT 0.21 Rectangular 1.732 1 0.12 ∞ Combined Standard Uncertainty Uc(f) = RSS 0.76 ∞				-				
Combined Standard Uncertainty Uc(f) = RSS 0.76 ∞								
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		• • • • • • • • • • • • • • • • • • • •	% Confidence	=				

6. Dielectric Property Measurements & System Check

6.1. Dielectric Property Measurements

The temperature of the tissue-equivalent medium used during measurement must also be within 18° C to 25° C and within $\pm 2^{\circ}$ C of the temperature when the tissue parameters are characterized.

The dielectric parameters must be measured before the tissue-equivalent medium is used in a series of SAR measurements. The parameters should be re-measured after each 3-4 days of use; or earlier if the dielectric parameters can become out of tolerance; for example, when the parameters are marginal at the beginning of the measurement series.

Tissue dielectric parameters were measured at the low, middle and high frequency of each operating frequency range of the test device.

The dielectric constant (ϵ r) and conductivity (σ) of typical tissue-equivalent media recipes are expected to be within \pm 5% of the required target values; but for SAR measurement systems that have implemented the SAR error compensation algorithms documented in IEEE Std 1528-2013, to automatically compensate the measured SAR results for deviations between the measured and required tissue dielectric parameters, the tolerance for ϵ r and σ may be relaxed to \pm 10%. This is limited to frequencies \leq 3 GHz.

Tissue Dielectric Parameters

FCC KDB 865664 D01 SAR Measurement 100 MHz to 6 GHz

Torget Frequency (MHz)	He	ead	Body					
Target Frequency (MHz)	$\varepsilon_{ m r}$	σ (S/m)	ε _r	σ (S/m)				
150	52.3	0.76	61.9	0.80				
300	45.3	0.87	58.2	0.92				
450	43.5	0.87	56.7	0.94				
835	41.5	0.90	55.2	0.97				
900	41.5	0.97	55.0	1.05				
915	41.5	0.98	55.0	1.06				
1450	40.5	1.20	54.0	1.30				
1610	40.3	1.29	53.8	1.40				
1800 – 2000	40.0	1.40	53.3	1.52				
2450	39.2	1.80	52.7	1.95				
3000	38.5	2.40	52.0	2.73				
5000	36.2	4.45	49.3	5.07				
5100	36.1	4.55	49.1	5.18				
5200	36.0	4.66	49.0	5.30				
5300	35.9	4.76	48.9	5.42				
5400	35.8	4.86	48.7	5.53				
5500	35.6	4.96	48.6	5.65				
5600	35.5	5.07	48.5	5.77				
5700	35.4	5.17	48.3	5.88				
5800	35.3	5.27	48.2	6.00				

Dielectric Property Measurements

SAR	Date	Band	Tissue	Frequency	Relative	Permittivity	(er)	Cor	nductivity (σ)
Lab	Date	(MHz)	Type	(MHz)	Measured	Target	Delta	Measured	Target	Delta
				2450	39.63	39.2	1.10%	1.79	1.80	-0.50%
D	7/31/2023	2450	Head	2400	39.66	39.3	0.92%	1.76	1.75	0.36%
				2500	39.52	39.1	0.98%	1.82	1.85	-1.62%
				2450	40.35	39.2	2.93%	1.78	1.80	-1.11%
D	8/7/2023	2450	Head	2400	40.42	39.3	2.86%	1.75	1.75	-0.04%
				2500	40.23	39.1	2.79%	1.81	1.85	-2.27%
				1900	39.30	40.0	-1.75%	1.42	1.40	1.07%
8	7/31/2023	1900	Head	1850	39.39	40.0	-1.53%	1.38	1.40	-1.29%
				1920	39.26	40.0	-1.85%	1.43	1.40	2.07%
				2450	38.51	39.2	-1.76%	1.80	1.80	-0.06%
8	7/31/2023	2450	Head	2400	38.59	39.3	-1.80%	1.76	1.75	0.42%
				2500	38.44	39.1	-1.78%	1.84	1.85	-0.92%
				2600	38.27	39.0	-1.90%	1.93	1.96	-1.89%
8	7/31/2023	2600	Head	2495	38.45	39.1	-1.77%	1.83	1.85	-0.90%
				2690	38.10	38.9	-2.05%	2.00	2.06	-3.03%
				3700	37.70	37.7	0.00%	3.13	3.12	0.41%
13	8/3/2023	3700	Head	3600	37.89	37.8	0.20%	3.03	3.01	0.53%
				3800	37.50	37.6	-0.23%	3.24	3.22	0.64%
		_		13	55.69	55.0	1.25%	0.72	0.75	-4.32%
2	7/20/2023	13	Head	12	55.86	55.0	1.56%	0.72	0.75	-4.31%
				14	55.36	55.0	0.65%	0.72	0.75	-4.32%

6.2. System Check

SAR system verification is required to confirm measurement accuracy, according to the tissue dielectric media, probe calibration points and other system operating parameters required for measuring the SAR of a test device. The system verification must be performed for each frequency band and within the valid range of each probe calibration point required for testing the device. The same SAR probe(s) and tissue-equivalent media combinations used with each specific SAR system for system verification must be used for device testing. When multiple probe calibration points are required to cover substantially large transmission bands, independent system verifications are required for each probe calibration point. A system verification must be performed before each series of SAR measurements using the same probe calibration point and tissue-equivalent medium. Additional system verification should be considered according to the conditions of the tissue-equivalent medium and measured tissue dielectric parameters, typically every three to four days when the liquid parameters are re-measured or sooner when marginal liquid parameters are used at the beginning of a series of measurements.

System Performance Check Measurement Conditions:

- The measurements were performed in the flat section of the TWIN SAM or ELI phantom, shell thickness: 2.0 ±0.2 mm (bottom plate) filled with Body or Head simulating liquid of the following parameters.
- The depth of tissue-equivalent liquid in a phantom must be ≥ 15.0 cm for SAR measurements ≤ 3 GHz and ≥ 10.0 cm for measurements > 3 GHz.
- The DASY system with an E-Field Probe was used for the measurements.
- The dipole was mounted on the small tripod so that the dipole feed point was positioned below the center
 marking of the flat phantom section and the dipole was oriented parallel to the body axis (the long side of the
 phantom). The standard measuring distance was 10 mm (above 1 GHz) and 15 mm (below 1 GHz) from dipole
 center to the simulating liquid surface.
- The coarse grid with a grid spacing of 15 mm was aligned with the dipole. For 5 GHz band - The coarse grid with a grid spacing of 10 mm was aligned with the dipole.
- Special 7x7x7 (below 3 GHz) and/or 8x8x7 (above 3 GHz) fine cube was chosen for the cube.
- Distance between probe sensors and phantom surface was set to 3 mm.
 For 5 GHz band Distance between probe sensors and phantom surface was set to 2.5 mm
- The dipole input power (forward power) was 100 mW.
- The results are normalized to 1 W input power.

System Check Results

The 1-g and 10-g SAR measured with a reference dipole, using the required tissue-equivalent medium at the test frequency, must be within $\pm 10\%$ of the manufacturer calibrated dipole SAR target. Refer to Appendix B for the SAR System Check Plots.

			Dipole Type		Mea	asured resu	ts for 1-g SA	R	Mea	sured result	s for 10-g SA	.R	
SAR Lab	Date	Tissue Type	& Serial Number	Dipole Cal. Due Date	Zoom Scan at 100 mW	Normalize to 1 W	Target (Ref. Value)	Delta ±10%	Zoom Scan at 100 mW	Normalize to 1 W	Target (Ref. Value)	Delta ±10%	Plot No.
D	7/31/2023	Head	D2450V2 SN: 899	4/18/2024	5.38	53.8	51.9	3.66%	2.61	26.1	24.4	6.97%	1
D	8/7/2023	Head	D2450V2 SN: 706	1/20/2024	4.99	49.9	52.3	-4.59%	2.40	24.0	24.5	-2.04%	2
8	7/31/2023	Head	D1900V2 SN: 5d163	10/28/2023	4.01	40.1	39.1	2.56%	2.10	21.0	20.4	2.94%	3
8	7/31/2023	Head	D2450V2 SN: 899	4/18/2024	5.57	55.7	51.9	7.32%	2.63	26.3	24.4	7.79%	4
8	7/31/2023	Head	D2600V2 SN: 1036	4/11/2024	5.97	59.7	55.4	7.76%	2.72	27.2	24.9	9.24%	5
13	8/3/2023	Head	D3700V2 SN: 1110	11/20/2023	6.72	67.2	64.1	4.85%	2.56	25.6	23.6	8.47%	6
			Dinolo Typo		Mea	asured resu	ts for 1-g SA	R	Mea	sured result	s for 10-g SA	R	
SAR Lab	i Date I	Tissue Type	2	Dipole Cal. Due Date	Zoom Scan (1 W)	Normalize to 1 W	Target (Ref. Value)	Delta ±10 %	Zoom Scan (1 W)	Normalize to 1 W	Target (Ref. Value)	Delta ±10 %	Plot No.
2	7/20/2023	Head	CLA13 SN: 1008	1/12/2024	0.509	0.509	0.544	-6.43%	0.314	0.314	0.338	-7.10%	7

6.3. Power Density System Performance Check

Per Nov 2017, TCB Workshop

System validation is required before a system is deployed for measurement.

System check is also required before each series of continuous measurement and, as applicable, repeated at least weekly.

Peak and spatially averaged power density at the peak location(s) must be compared to calibrated results according to the defined test conditions:

- the same spatial resolution and measurement region used in the waveguide calibration should be applied to system validation and system check.
- 1 cm² and 4 cm² spatial averaging have been recommended in the AHG10 draft TR with reference targets available for specific waveguide.
- power density distribution should also be verified, both spatially (shape) and numerically (level) through visual inspection for noticeable differences.
- the measured results should be within 10% of the calibrated targets.

The system components, software settings and other system parameters shall be the same as those used for the compliance tests. The system check shall be performed at the closest probe calibration frequency point as in the compliance tests, e.g., if the EUT operates at 35 GHz, it is recommended to perform the validation at 30 GHz.

System Check Results

	SAR Lab	Date	Frequency (GHz)	5G Verification Source SN	Source Cal. Due Data	Measured psPDn (W/m ²) over 4cm ²	Normalized to 19.9 dBm (W/m²)	Target psPDn (W/m ²) over 4cm ²	Deviation (dB)	Delta ±10 %	Measured psPDtot (W/m ²) over 4cm ²	Normalized to 19.9 dBm (W/m²)	Target psPDtot (W/m ²) over 4cm ²	Deviation (dB)	Delta ±10 %	Plot
Г	3	8/18/2023	10	1015	9/13/2023	53.9	61.2	56.0	0.38	9%	54.2	61.5	57.1	0.32	8%	8

Note(s):

- The input power level used for system performance check is the same input power level as calibration data, 19.3 dBm.
- Refer to Appendix B for the System Performance Check Plot.

7. Test Rationale

7.1. Purpose

This application for certification is leveraging the data reuse procedure from TCB workshop April 2021; RF Exposure Procedures (Remarks on Test Reductions via Data Referencing for Closely Related Products) based on reference FCC ID: BCG-E8440A (UL SAR report# 14523772-S1) and (UL PD report # 14523772-S10) to cover variants FCC ID: BCG-ECG8441A and BCG-ECG8442A. The major difference between the reference model and the variant models is that support for some LTE/5GNR bands and MSS is disabled via software in the variant models. All other circuitry and features are identical. The data reuse test plan was approved via manufacturer KDB inquiry.

7.2. Data Reuse Approach

Full RF exposure testing was performed on the reference model. The configurations with the highest SAR results for each equipment class and highest PD result were identified. These configurations were tested on the variant models.

The variation in SAR/PD results was well within the uncertainty budget of the SAR/PD test equipment. The variant SAR/PD results and worst-case reference model SAR/PD results are summarized in § 1.

For operations in the UNII bands the operating band with the highest exposure ratio across all supported UNII bands (1, 2A, 2C, 3, 5-8) was selected for the spot checks. This was UNII band 6.

8. Measured and Reported (Scaled) Results

8.1. A3106 Spot Check Results

Equipment Class	Technology	Band	Ante		posure	Mode	Power Mode	Dist (mm)	Test Positio	ın C	Channel	Freq. (MHz	Duty Cycle (%)	Max Output Pwr (dBm)	Meas. (dBm)	A3105 1-g Meas. (W/kg)	A3105 1-g Scaled (W/kg)	A3105 10-g Meas. (W/kg)	A3105 10-g Scaled (W/kg)	A3106 1-g Meas. (W/kg)	A3106 1-g Scaled (W/kg)	A3106 10-g Meas (W/kg)	A3106 10-g Scaled (W/kg)	Plot No.
TNE	LTE	B53	AN	Γ2 Body	& Hotspot	QPSK	Mode B	5	Back		60197	2489.2		20.5	19.9	0.817	0.938	0.321	0.369	0.689	0.791	0.279	0.320	1
PCE	LTE	B41 FCC P	C3 AN	T2 Body	& Hotspot	QPSK	Mode B	5	Back		40185	2549.5		20.5	19.9	0.825	0.947	0.328	0.377	0.694	0.797	0.285	0.327	2
CBE	FR1	n48	AN	Γ9 Body	& Hotspot	DFT-s-OFDM π/2 BPSK	Mode B	5	Back		642888	3643.3		20.8	20.1	0.808	0.949	0.949	1.115	0.725	0.852	0.264	0.310	3
DTS	Wi-Fi	2.4 GHz	: AN	Г4 Н	otspot	802.11b	Power State 1 Mode B	5	Edge Right		11	2462.0	100%	19.8	18.4	0.826	1.132	0.345	0.473	0.659	0.903	0.277	0.379	4
DSSS	Bluetooth	(2.4 GHz) AN	Г4 Н	otspot	LE (1 Mbps)	PStandalone Pow er Mode B	5	Edge Right		39	2441.0	76.60%	20.5	19.1	0.666	0.917	0.280	0.386	0.673	0.927	0.282	0.388	5
Equipment Class	Technolog	ıy	Band	Anten		F Exposure Condition	Mode	Po	wer Mode	Di (m	ist m)	t Position	Channe	l Freq. (I	MHz) Duty	Cycle Ma %) Pw	x Output rr (dBm)	Meas. (dBm)	A3105 10-g Mea (W/kg)	A310 s. 10-g Sci (W/kg	iled 10-g	3106 Meas. 1 //kg)	A3106 0-g Scaled (W/kg)	Plot No.
DXX	NFC		13.56MHz	Primar	у	Extremity	Type A				0 E	dge Top		13.5	6				0.006		0	.004		6
Equipment Class	Technolog	,	Band	Antenna		exposure	Mode	Powe		Dist mm)	Test Po	sition	Channel	Freq. (MHz)	Duty Cycle (%)	Max Outp	Meas.	dBm) psPE	A3105 Otot Meas. p W/cm²)	A3105 os PDtot Scale (mW/cm²)	A31 d psPDtot (mW/	Meas. ps	A3106 PDtot Scaled (mW/cm²)	Plot No.
U-NII	6E		U-NII 6	ANT 6	Body	& Hotspot 80	02.11ax (HE80)		tate 1 & 2 Mode B	2	Bac	:k	103	6465.00	98.24%	8.75	8.2	15	0.615	0.702	0.4	98	0.569	7

8.2. A3108 Spot Check Results

Equipment Class	Technology	Band	Antenna	RF Exposus Condition		Power Mode	Dist (mm)	Test Position	Channel	Freq. (MHz)	Duty Cycle (%)	Max Output Pwr (dBm)	Meas. (dBm)	A3105 1-g Meas. (W/kg)	A3105 1-g Scaled (W/kg)	A3105 10-g Meas. (W/kg)	A3105 10-g Scaled (W/kg)	A3108 1-g Meas. (W/kg)	A3108 1-g Scaled (W/kg)	A3108 10-g Meas. (W/kg)	3108 10-g Scaled (W/kg)	Plot No.
PCE	LTE	B41 FCC PC	3 ANT 2	Body & Hots	pot QPSK	Mode B	5	Back	40185	2549.5		20.5	19.9	0.825	0.947	0.328	0.377	0.683	0.784	0.278	0.319	8
CBE	FR1	n48	ANT 9	Body & Hots	pot DFT-s-OFDM1 BPSK	π/2 Mode B	5	Back	642888	3643.3		20.8	20.1	0.808	0.949	0.949	1.115	0.660	0.775	0.251	0.295	9
DTS	Wi-Fi	2.4 GHz	ANT 4	Hotspot	802.11b	Pow er State 1 Mode B	5	Edge Right	11	2462.0	99.84%	19.8	18.4	0.826	1.132	0.345	0.473	0.568	0.778	0.238	0.326	10
DSSS	Bluetooth	(2.4 GHz)	ANT 4	Hotspot	LE (1 Mbps) PStandalone Pow er Mode E		Edge Right	39	2441.0	76.60%	20.5	19.1	0.666	0.917	0.280	0.386	0.459	0.632	0.194	0.267	11
Equipment Class	Technolog	ЭУ	Band	Antenna	RF Exposure Condition	Mode	Po	wer Mode	Dist (mm)	st Position	Channe	Freq. (i	MHz) Duty	Cycle Max %) Pwr	Output (dBm)	eas. (dBm)	A3105) 10-g Meas (W/kg)	A3105 s. 10-g Sca (W/kg	aled 10-g		3108)-g Scaled (W/kg)	Plot No.
DXX	NFC	1	3.56MHz	Primary	Extremity	Type A			0	Edge Top		13.5	6				0.006		0.	006		12
Equipment Class	Technolog	y I	Band		RF Exposure Condition	Mode	Power	Mode Dis		sition C	hannel F	req. (MHz)	Duty Cycle (%)	Max Output Pwr (dBm)	t Meas. (di	Bm) psPD	A3105 Itot Meas. p: W/cm²)	A3105 sPDtot Scale (mW/cm²)	d psPDtot (mW/c	Meas. psF	A3108 PDtot Scaled (mW/cm²)	Plot No.
U-NII	6E		J-NII 6	ANT 6	Body &	302.11ax (HE80)	Pow er Sta	ate 1 & 2	Bad		103	6465.00	98.24%	8.75	8.25		0.615	0.702	0.52		0.604	13

Appendixes

Refer to separated files for the following appendixes.

Appendix A: SAR Setup Photos

Appendix B: SAR System Check Plots

Appendix C: SAR Highest Test Plots

Appendix D: SAR Tissue Ingredients

Appendix E: SAR Probe Certificates

Appendix F: SAR Dipole Certificates

Appendix G: PD Verification source Certificate

END OF REPORT